

Notice of References Cited

Application/Control No.

10/040,797

Applicant(s)/Patent Under
Reexamination
GOLDFINE ET AL.

Examiner

Jeffrey R. West

Art Unit

2857

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,223,796	06-1993	Waldman et al.	324/687
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NON-PATENT DOCUMENTS

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	V	Sadiku, "Elements of Electromagnetics", Oxford University Press. pp 289-290 1995.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.